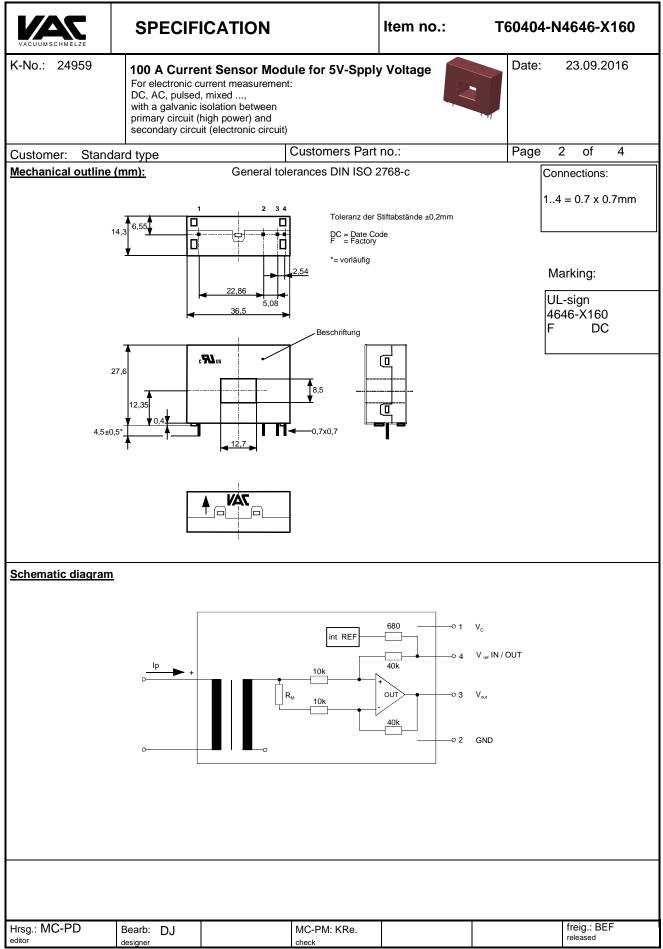
	SPECIFICATION	Item r	10.:	T60404-N	N4646-X160
K-No.: 24959	<b>100 A Current Sensor Module for 5V-</b> For electronic current measurement: DC, AC, pulsed, mixed, with a galvanic isolation between primary circuit (high power) and secondary circuit (electronic circuit)	Spply Voltag	e	Date:	23.09.2016
Customer: Stand	dard type Customers	Part no.:		Page	1 of 4
Description	<u>Characteristics</u>		pplications	•	
<ul> <li>Closed loop (compe Current Sensor with field probe</li> <li>Printed circuit board</li> <li>Casing and materia</li> </ul>	ensation) n magnetic d mounting • Excellent accuracy • Very low offset current • Very low temperature dependency current drift	M aj y and offset	<ul> <li>ainly used fo</li> <li>pplications:</li> <li>AC variated drives</li> <li>Static core</li> <li>Battery se</li> <li>Switched</li> <li>Power Su</li> </ul>	r stationary opera	ons pplies (SMPS) ig applications
Electrical data – Ra	atings	min.	typ.	max.	Einheit
I <sub>PN</sub>	Primary nominal r.m.s. current		10		A
I <sub>PN</sub> V <sub>out</sub>	Output voltage @ I <sub>P</sub>			י∪ <sub>8ef</sub> ± (0.625*I <sub>P</sub> /I <sub>I</sub>	
V <sub>out</sub>	Output voltage @ $I_P$ Output voltage @ $I_P$ =0, $T_A$ =25°C			$g_{ef} \pm (0.025 \text{ p/l})$	PN) V V
v out V <sub>Ref</sub>	Reference voltage external	0	V H	4	V
V <sub>Ref</sub>	Reference voltage internal	0	2	$\frac{1}{5 \pm 0.005}$	V
K <sub>N</sub>	Turns ratio			1000	v
	ic performance data		•	1000	
		min.	typ.	max.	Unit
I <sub>P,max</sub> X	Max. measuring range	±230		1	%
	Accuracy @ I <sub>PN</sub> , T <sub>A</sub> = 25°C			-	
				0.1	%
V <sub>out</sub> -2,5V	Offset voltage @ I <sub>P</sub> =0, T <sub>A</sub> = 25°C	<b>^</b>	0	±2.5	mV
	Temperature drift of Vout @ IP=0, TA= -4085	°C	3	10	ppm/K
$\Delta V_{out}/2,5V/\Delta T$	•				μs
tr	Response time @ 80% von I <sub>PN</sub>		1		·
t <sub>r</sub> ∆t (I <sub>P,max</sub> )	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs	DC 10	1		μs
t <sub>r</sub> ∆t (I <sub>P,max</sub> ) f	Response time @ 80% von I <sub>PN</sub>	DC10	1		·
t <sub>r</sub> ∆t (I <sub>P,max</sub> ) f	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs		1 0	may	μs kHz
t <sub>r</sub> ∆t (I <sub>P,max</sub> ) f General data	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs Frequency bandwidth	min.	1	<u>max.</u> +85	µs kHz Unit
t <sub>r</sub> ∆t (I <sub>P,max</sub> ) f General data T <sub>A</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs Frequency bandwidth Ambient operating temperature	<mark>min.</mark> -40	1 0	+85	μs kHz <mark>Unit</mark> °C
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs         Frequency bandwidth         Ambient operating temperature         Ambient storage temperature	min.	1 D typ.		μs kHz <b>Unit</b> °C °C
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub> m	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs         Frequency bandwidth         Ambient operating temperature         Ambient storage temperature         Mass	<mark>min.</mark> -40 -40	1 0 <b>typ.</b> 18	+85 +85	μs kHz <b>Unit</b> °C °C g
t <sub>r</sub> ∆t (I <sub>P,max</sub> ) f General data T <sub>A</sub> Ts m V <sub>C</sub>	<ul> <li>Response time @ 80% von I<sub>PN</sub></li> <li>Delay time at di/dt = 100 A/µs</li> <li>Frequency bandwidth</li> <li>Ambient operating temperature</li> <li>Ambient storage temperature</li> <li>Mass</li> <li>Supply voltage</li> </ul>	<mark>min.</mark> -40	1 0 <b>typ.</b> 18 5	+85	μs kHz <sup>°</sup> C °C g V
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub> m V <sub>C</sub> I <sub>C0</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/µs Frequency bandwidth Ambient operating temperature Ambient storage temperature Mass Supply voltage Current consumption	<mark>min.</mark> -40 -40 4.75	1 0 <b>typ.</b> 18	+85 +85	μs kHz <sup>°</sup> C °C g V mA
$\begin{array}{c} t_r \\ \Delta t \; (I_{P,max}) \\ f \end{array} \\ \hline \textbf{General data} \\ \hline \textbf{T}_A \\ \hline \textbf{T}_S \\ \textbf{m} \\ V_C \\ \hline \textbf{I}_{C0} \\ \textbf{S}_{clear} \end{array}$	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/µs Frequency bandwidth Ambient operating temperature Ambient storage temperature Mass Supply voltage Current consumption Clearance (component without solder pad)	min. -40 -40 4.75 12	1 0 <b>typ.</b> 18 5	+85 +85	μs kHz <sup>°</sup> C °C g V
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub> m V <sub>C</sub> I <sub>C0</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/µs Frequency bandwidth Ambient operating temperature Ambient storage temperature Mass Supply voltage Current consumption	<mark>min.</mark> -40 -40 4.75	1 0 <b>typ.</b> 18 5	+85 +85	μs kHz <sup>°</sup> C <sup>°</sup> C g V w mA mm
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub> m V <sub>C</sub> I <sub>C0</sub> S <sub>clear</sub> S <sub>creep</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/µs Frequency bandwidth Ambient operating temperature Ambient storage temperature Mass Supply voltage Current consumption Clearance (component without solder pad) Creepage (component without solder pad) System voltage overvoltage category III Working voltage (table 3 acc. to IEC 61800	min. -40 -40 4.75 12 12	1 0 <b>typ.</b> 18 5	+85 +85 5.25 600	μs kHz <sup>°</sup> C <sup>°</sup> C g V mA mm mm V <sub>RMS</sub>
t <sub>r</sub> Δt (I <sub>P,max</sub> ) f General data T <sub>A</sub> T <sub>S</sub> m V <sub>C</sub> I <sub>C0</sub> S <sub>clear</sub> S <sub>creep</sub> V <sub>sys</sub> V <sub>work</sub>	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/μs         Frequency bandwidth         Ambient operating temperature         Ambient storage temperature         Mass         Supply voltage         Current consumption         Clearance (component without solder pad)         Creepage (component without solder pad)         System voltage         Working voltage         (table 3 acc. to IEC 61800)         overvoltage category 2	min. -40 -40 4.75 12 12	1 0 <b>typ.</b> 18 5	+85 +85 5.25 600 1000	μs kHz <sup>°</sup> C <sup>°</sup> C g V mA mm mm V <sub>RMS</sub> V <sub>RMS</sub>
$\begin{array}{c} t_r \\ \Delta t \left( I_{P,max} \right) \\ f \end{array} \\ \hline \textbf{General data} \\ \hline \textbf{General data} \\ \hline \textbf{T}_A \\ \hline \textbf{T}_S \\ \textbf{m} \\ \hline \textbf{V}_C \\ \hline \textbf{I}_{C0} \\ \hline \textbf{S}_{clear} \\ \hline \textbf{S}_{creep} \\ \hline \textbf{V}_{sys} \end{array}$	Response time @ 80% von I <sub>PN</sub> Delay time at di/dt = 100 A/µs Frequency bandwidth Ambient operating temperature Ambient storage temperature Mass Supply voltage Current consumption Clearance (component without solder pad) Creepage (component without solder pad) System voltage overvoltage category III Working voltage (table 3 acc. to IEC 61800	min. -40 -40 4.75 12 12	1 0 <b>typ.</b> 18 5	+85 +85 5.25 600	μs kHz <sup>°</sup> C <sup>°</sup> C g V mA mm mm V <sub>RMS</sub>



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VACUUMSCHMELZE	SPEC		Item no	0.:	T60404-N4	646-X160
-No.: 24959	For electro DC, AC, pu with a galva primary cire	Irrent Sensor Module for nic current measurement: ilsed, mixed, anic isolation between cuit (high power) and circuit (electronic circuit)	or 5V-Spply Voltage		Date: 2	23.09.2016
ustomer: Standa	ard type	Custo	omers Part no.:		Page 3	of 4
lectrical Data						
. /	NA	and the second second	min.	typ.	max.	Unit
V <sub>Ctot</sub>		supply voltage (without function	,		6	V
С		rent with primary current	16MA	∧ +I <sub>p</sub> *K <sub>N</sub> +V₀	ut/RL	mA
out,SC		it output current		±20		mA
Rs	-	coil resistance @ T <sub>A</sub> =85°C			14	Ω
R <sub>i,Ref</sub>		sistance of Reference input		670		Ω
Ri,(Vout)		stance of Vout			1	Ω
RL	External re	commended resistance of V	/ <sub>out</sub> 1			kΩ
CL	External re	commended capacitance of	Vout		500	pF
ΔΧ <sub>ΤΙ</sub> /ΔΤ	Temperatu	re drift of X @ T <sub>A</sub> = -40 +8	35 °C		40	ppm/K
$\Delta V_0 = \Delta (V_{out} - V_{Ref})$	Sum of any	offset drift including:		2	6	mV
V <sub>0t</sub>	Long term	drift of V <sub>0</sub>		1		mV
V <sub>0T</sub>	Temperatu	re drift von $V_0 @ T_A = -40 \dots$	+85°C	1		mV
V <sub>0H</sub>	Hystereses	s of $V_{out}$ @ $I_P=0$ (after an over	load of 10 x I <sub>PN</sub> )		0.7	mV
$\Delta V_0 / \Delta V_C$	Supply volt	age rejection ratio			1	mV/V
Voss	Offsetripple	e (with 1 MHz- filter first orde	er)		20	mV
V <sub>oss</sub>	Offsetripple	e (with 100 kHz- filter firdt or	der)	2.5	6	mV
				=	•	
V <sub>oss</sub>	Offsetripple	e (with 20 kHz- filter first ord		0.7	1.5	mV
V <sub>oss</sub> C <sub>k</sub>	Maximum Mechanica	(with 20 kHz- filter first ord possible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours	er) primary – secondary) /3		-	mV pF
C <sub>k</sub>	Maximum Mechanica Settings: 1	oossible coupling capacity ( I stress according to M3209	er) primary – secondary) /3	0.7 6	1.5	
C <sub>k</sub> <u>spection</u> (Measure V <sub>out</sub> (SC) (V)	Maximum p Mechanica Settings: 1 ment after tem M3011/6:	bossible coupling capacity ( I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours	er) primary – secondary) /3 s at room temperature, S	0.7 6 C = significa	1.5	
C <sub>k</sub> <b>aspection</b> (Measurer V <sub>out</sub> (SC) (V) V <sub>out</sub> - V <sub>Ref</sub> (I <sub>P</sub> =0) (V) V <sub>d</sub> (V)	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014:	bossible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40	0.7 6 C = significa	1.5 nt characteristic) $625\pm0.7\%$ $\pm 0.0025$ 1.8	pF mV V kV
C <sub>k</sub> <b>spection</b> (Measurer V <sub>out</sub> (SC) (V) V <sub>out</sub> - V <sub>Ref</sub> (I <sub>P</sub> =0) (V) V <sub>d</sub> (V)	Maximum µ Mechanica Settings: 1 ment after tem M3011/6: M3226:	oossible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40	0.7 6 C = significa	1.5 nt characteristic) 625±0.7% ± 0.0025	pF mV V
C <sub>k</sub> spection (Measurer V <sub>out</sub> (SC) (V) V <sub>out</sub> -V <sub>Ref</sub> (I <sub>P</sub> =0) (V) V <sub>d</sub> (V) V <sub>e</sub> (AC	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4):	oossible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub>	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40	0.7 6 C = significa	1.5 nt characteristic) $625\pm0.7\%$ $\pm 0.0025$ 1.8 1500	pF mV V kV V <sub>RMS</sub>
$C_k$ $N_{out}(SC)$ (V) $V_{out} - V_{Ref}(I_P=0)$ (V) $V_d$ (V) $V_e$ (AC $V_pe$ Testing (Pin 1-	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4):	oossible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub>	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024	0.7 6 C = significa -80Hz)	1.5 nt characteristic) $625\pm0.7\%$ $\pm 0.0025$ 1.8 1500	pF mV V kV V <sub>RMS</sub>
$C_k$ <b>spection</b> (Measured $V_{out}$ (SC) (V) $V_{out}$ – $V_{Ref}$ (Ip=0) (V) $V_d$ (V) $V_e$ (AC <b>ype Testing</b> (Pin 1- $V_W$	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4): 4 to inner hole HV transie	Dossible coupling capacity ( I stress according to M3209 D Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub>	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024	0.7 6 C = significa -80Hz)	1.5 nt characteristic) 625±0.7% ± 0.0025 1.8 1500 1875	pF mV V kV V <sub>RMS</sub> V <sub>RMS</sub>
C <sub>k</sub> <u>spection</u> (Measured V <sub>out</sub> (SC) (V) V <sub>out</sub> V <sub>Ref</sub> (I <sub>P</sub> =0) (V) V <sub>d</sub> (V) V <sub>e</sub> (AC <u>ype Testing</u> (Pin 1-	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4): 4 to inner hole HV transien Testing vol	possible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub>	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024	0.7 6 C = significa -80Hz) rm)	1.5 nt characteristic) 625±0.7% ± 0.0025 1.8 1500 1875 8	pF mV V kV V <sub>RMS</sub> V <sub>RMS</sub>
C <sub>k</sub> <b>spection</b> (Measurea V <sub>out</sub> (SC) (V) V <sub>out</sub> - V <sub>Ref</sub> (I <sub>P</sub> =0) (V) V <sub>d</sub> (V) V <sub>e</sub> (AC <b>ype Testing</b> (Pin 1- V <sub>W</sub> V <sub>d</sub>	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4): 4 to inner hole HV transien Testing vol	possible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub>	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024	0.7 6 C = significa -80Hz) rm)	1.5 nt characteristic) 625±0.7% ± 0.0025 1.8 1500 1875 8 3.6	pF mV V kV V <sub>RMS</sub> V <sub>RMS</sub>
C <sub>k</sub> <b>spection</b> (Measurer Vout (SC) (V) Vout VRef (Ip=0) (V) Vd (V) Ve (AC <b>ype Testing</b> (Pin 1- Vw Vd Ve <b>pplicable documer</b> urrent direction: A posi nclosures according to emperature of the prime	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4): -4 to inner hole HV transie Testing vol Partial disc with V <sub>vor</sub>	possible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub> ) ht test according to M3064 ( tage to M3014 harge voltage acc.M3024	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024 1,2 μs / 50 μs-wave fo	0.7 6 C = significa -80Hz) rm) (5 s)	1.5 nt characteristic) 625±0.7% ± 0.0025 1.8 1500 1875 8 3.6 1500	pF mV V kV V <sub>RMS</sub> V <sub>RMS</sub>
C <sub>k</sub> <b>spection</b> (Measurer Vout (SC) (V) Vout VRef (Ip=0) (V) Vd (V) Ve (AC <b>ype Testing</b> (Pin 1- Vw Vd Ve <b>pplicable documer</b> urrent direction: A posi nclosures according to emperature of the prime	Maximum p Mechanica Settings: 1 ment after tem M3011/6: M3226: M3014: QL 1/S4): -4 to inner hole HV transie Testing vol Partial disc with V <sub>vor</sub>	possible coupling capacity (p I stress according to M3209 0 Hz, 1 min/Oktave, 2 hours perature balance of the sample Output voltage vs. internal Offset voltage Test voltage, RMS, 1 s pin 1-4 to inner hole Partial discharge voltage a with V <sub>vor</sub> ) nt test according to M3064 (tage to M3014 harge voltage acc.M3024	er) primary – secondary) /3 s at room temperature, S reference (I <sub>P</sub> =100A, 40 acc.M3024 1,2 μs / 50 μs-wave fo	0.7 6 C = significa -80Hz) rm) (5 s)	1.5 nt characteristic) 625±0.7% ± 0.0025 1.8 1500 1875 8 3.6 1500 1875	pF mV V kV V <sub>RMS</sub> V <sub>RMS</sub>

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